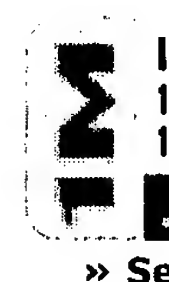


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L1	7223	((711/119.ccls. or 711/131.ccls. or 711/144-145.ccls. or 711/150.ccls. or 711/161-162.ccls. or 711/168.ccls. or 711/205-207.ccls. or 711/3.ccls. or 711/149-150.ccls. or 711/154.ccls. or 711/141.ccls.))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/05 14:42
L2	975	(712/221-222.ccls. or 712/244.ccls.)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/05 14:43
L3	199	(708/495.ccls. or 708/507.ccls.)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/05 14:43
L4	466	((((tlb or (translation adj5 (buffer or unit) or atu)) near5 (second or another or master or two or plural or multiple or several)) same (parallel or simultaneous\$2 or concurrent\$2))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/05 14:50
L5	8358	1 or 2 or 3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/05 14:50
L6	91	4 and 5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/05 14:51
L7	69	6 and (@ad<="19991217" or @rlad<="19991217")	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/05 15:23
L8	7673	integer same (floating adj2 point)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/05 14:53

L9	17	7 and 8	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/05 15:19
L10	30	4 same port	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/05 15:20
L11	6	10 and 7	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/05 15:23
L12	34	lyon-terry\$.in.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/05 15:23
L13	6	4 and 12	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/05 15:23
L14	6	13 and (@ad<="19991217" or @rlad<="19991217")	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/05 15:23

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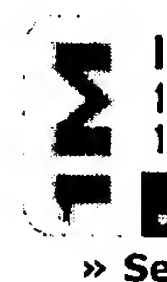
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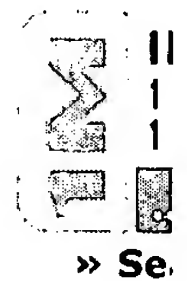
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 Workload Characterization: Methodology and Case Studies, 1998 , 29 Nov. 19
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